

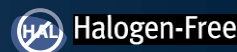
# EPC2206 – Automotive 80 V (D-S) Enhancement Mode Power Transistor

$V_{DS}$ , 80 V

$R_{DS(on)}$ , 2.2 mΩ

$I_D$ , 90 A

AEC-Q101



Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

## Maximum Ratings

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	80	V
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ )	90	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	390	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	

## Thermal Characteristics

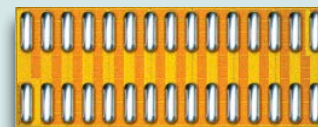
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

## Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 500 \mu\text{A}$	80			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 80 \text{ V}$		20	200	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 6 \text{ V}$ , $T_J = 25^\circ\text{C}$		0.02	4	mA
	Gate-to-Source Forward Leakage#	$V_{GS} = 6 \text{ V}$ , $T_J = 125^\circ\text{C}$		0.1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		20	200	$\mu\text{A}$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 13 \text{ mA}$	0.7	1.2	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 29 \text{ A}$		1.8	2.2	mΩ
$V_{SD}$	Source-Drain Forward Voltage#	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.5		V

All measurements were done with substrate connected to source.  
# Defined by design. Not subject to production test.



**EPC2206** eGaN® FETs are supplied only in passivated die form with solder bars.  
Die Size: 6.05 x 2.3 mm

## Applications

- 48 V Automotive Power
- Open Rack Server Architectures
- High Power Density DC-DC Converters
- Isolated Power Supplies
- Class D Audio
- Low Inductance Motor Drive

## Benefits

- Ultra High Efficiency
- No Reverse Recovery
- Ultra Low  $Q_G$
- Small Footprint



Dynamic Characteristics<sup>#</sup> (T<sub>j</sub> = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V		1610	1940	pF
C <sub>RSS</sub>	Reverse Transfer Capacitance			15		
C <sub>OSS</sub>	Output Capacitance			1100	1650	
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V <sub>DS</sub> = 0 to 40 V, V <sub>GS</sub> = 0 V		1450		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)			1790		
R <sub>G</sub>	Gate Resistance			0.3		Ω
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 29 A		15	19	nC
Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 29 A		4.1		
Q <sub>GD</sub>	Gate-to-Drain Charge			3		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			2.7		
Q <sub>OSS</sub>	Output Charge	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V		72	108	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

<sup>#</sup> Defined by design. Not subject to production test.

Note 2: C<sub>OSS(ER)</sub> is a fixed capacitance that gives the same stored energy as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Note 3: C<sub>OSS(TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

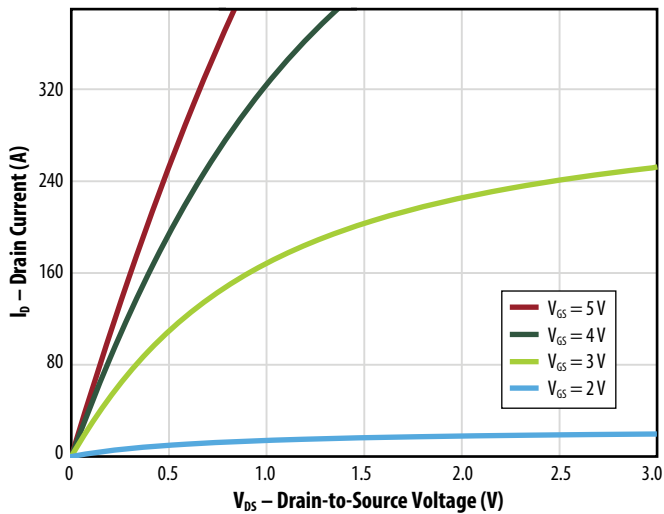


Figure 2: Typical Transfer Characteristics

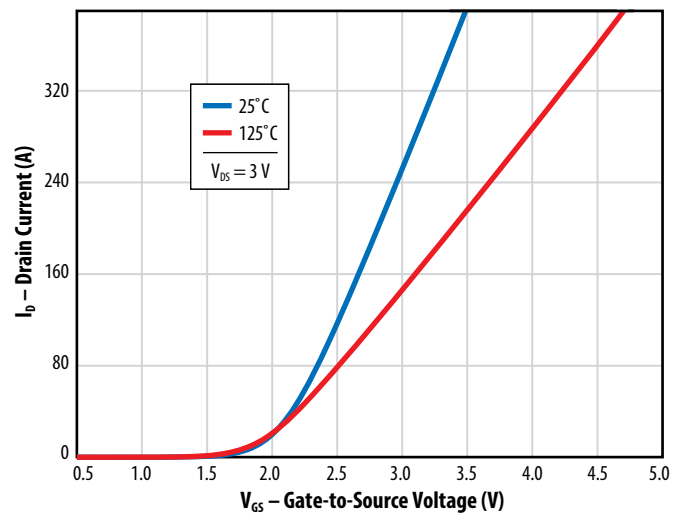


Figure 3: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Drain Currents

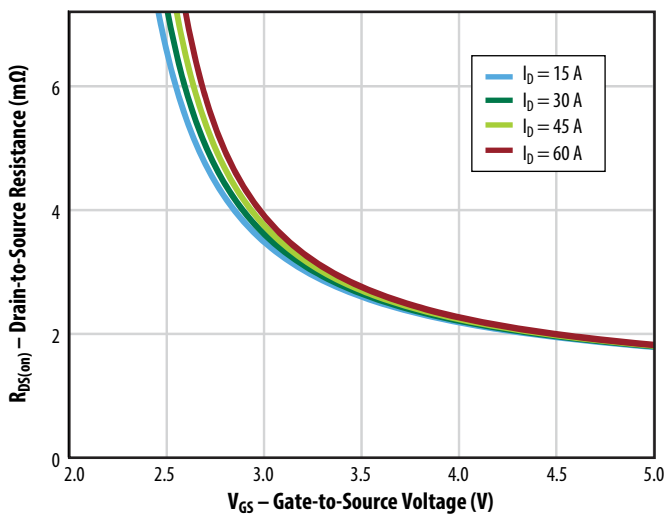


Figure 4: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

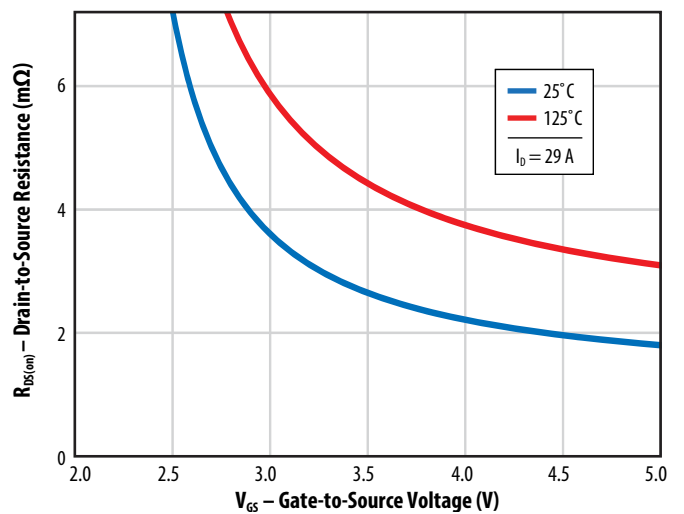


Figure 5a: Typical Capacitance (Linear Scale)

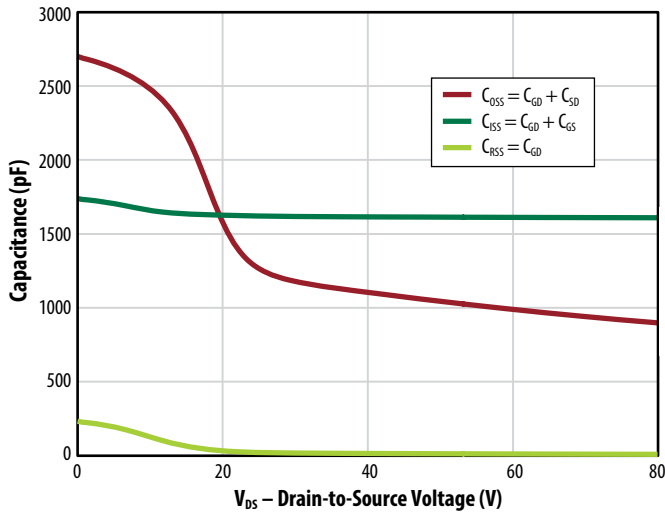


Figure 5b: Typical Capacitance (Log Scale)

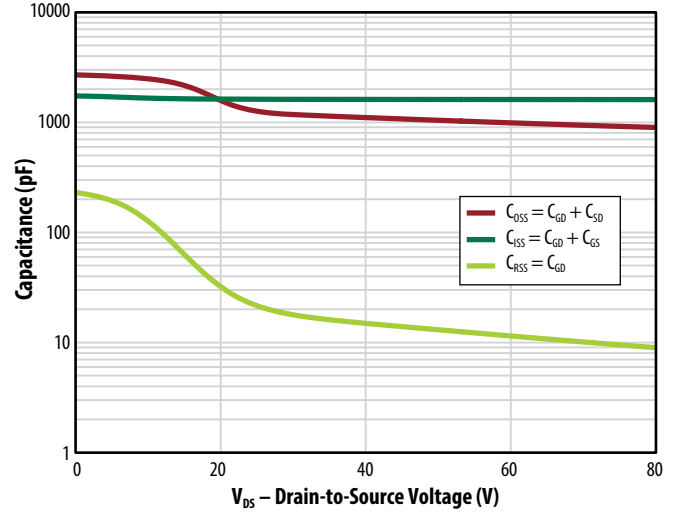


Figure 6: Typical Output Charge and  $C_{oss}$  Stored Energy

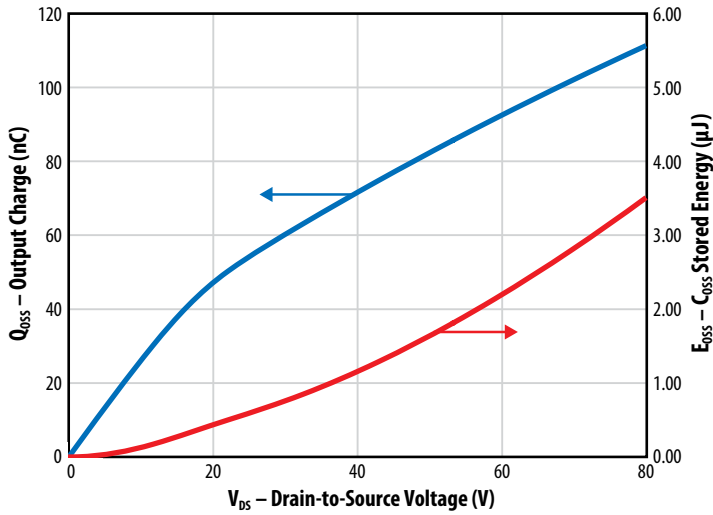


Figure 7: Typical Gate Charge

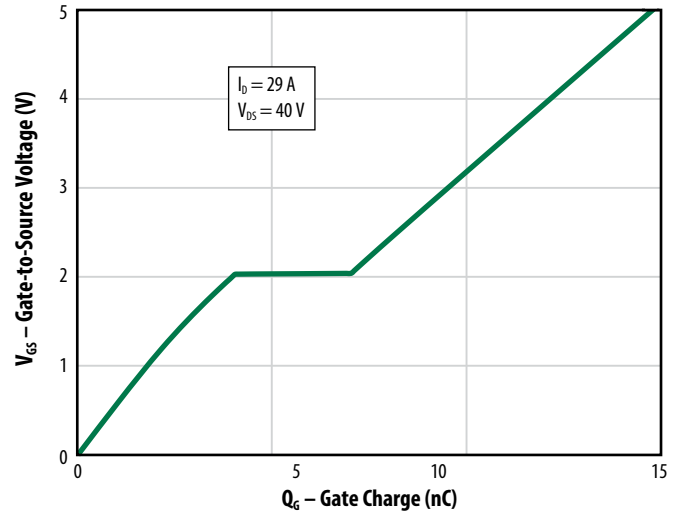


Figure 8: Reverse Drain-Source Characteristics

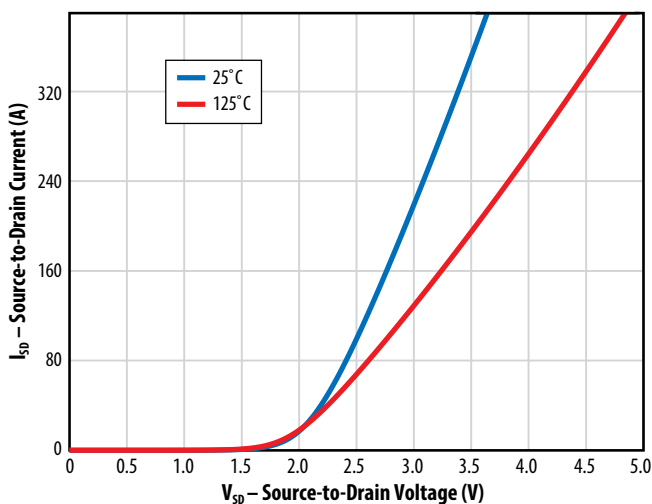
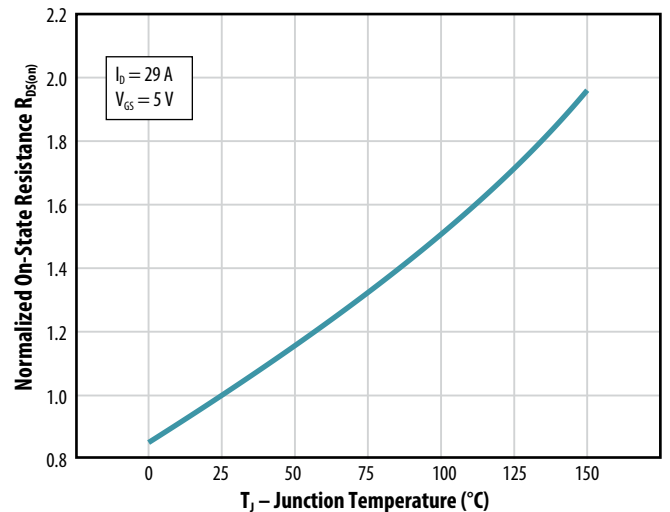


Figure 9: Normalized On-State Resistance vs. Temperature



Note: Negative gate drive voltage increases the reverse drain-source voltage.  
EPC recommends 0 V for OFF.

Figure 10: Normalized Threshold Voltage vs. Temperature

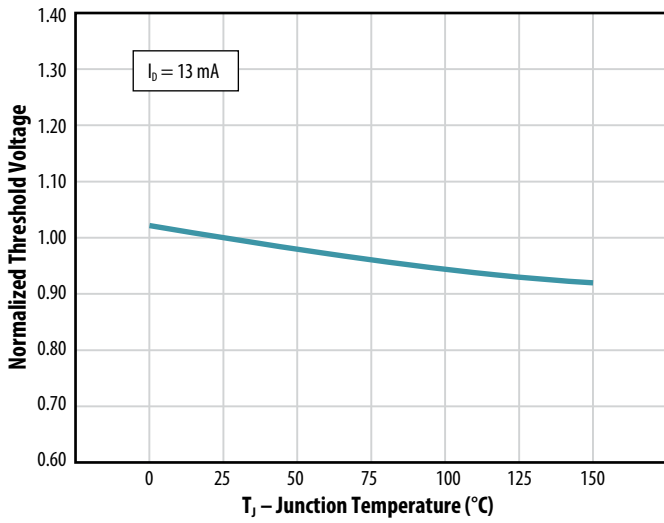


Figure 11: Safe Operating Area

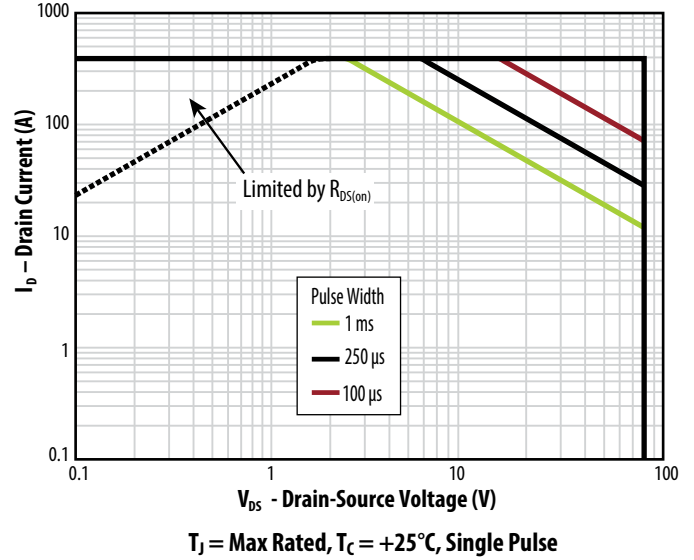
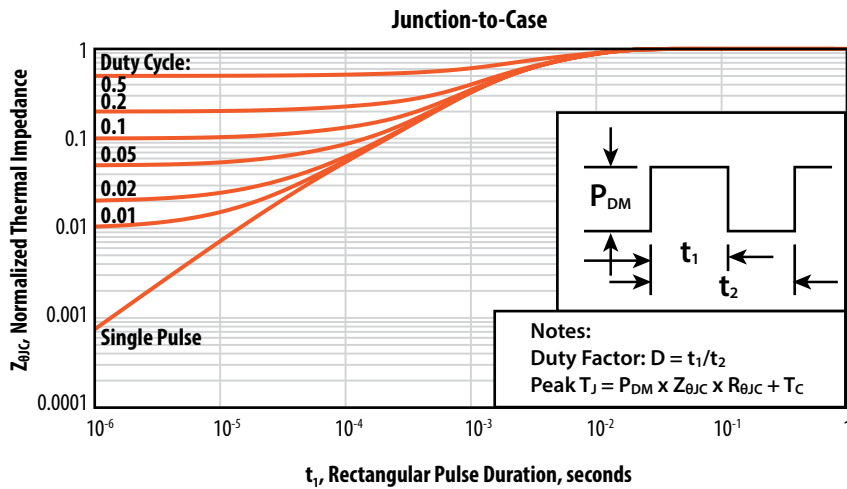
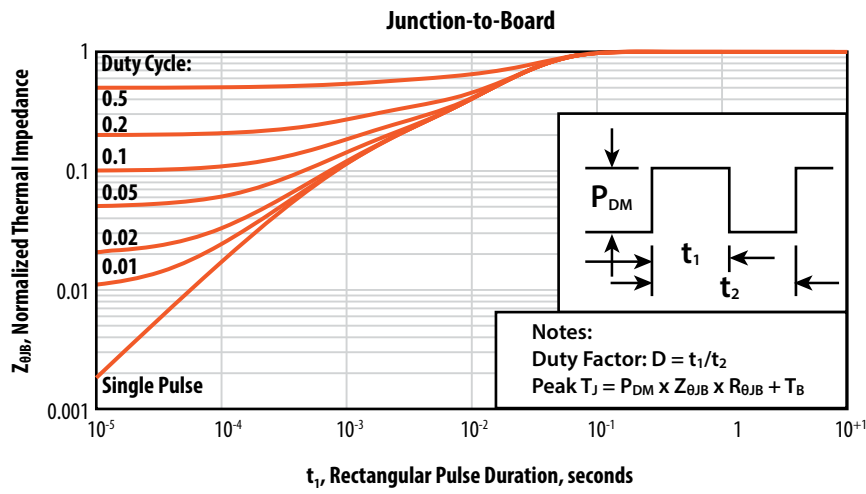
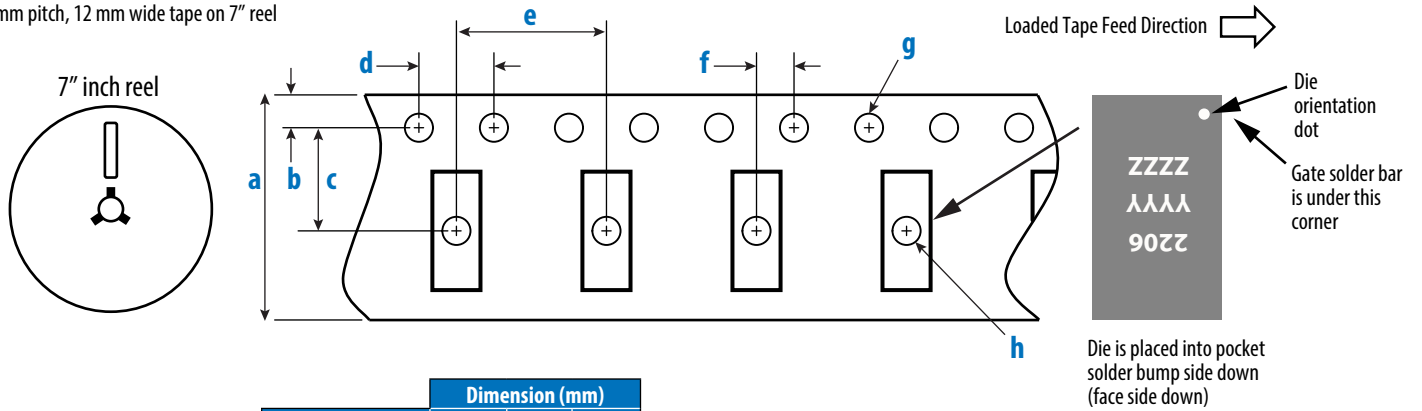


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

8 mm pitch, 12 mm wide tape on 7" reel

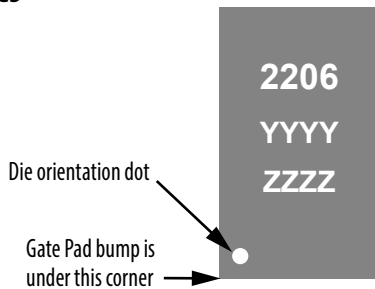


EPC2206 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.50	1.50	1.75

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

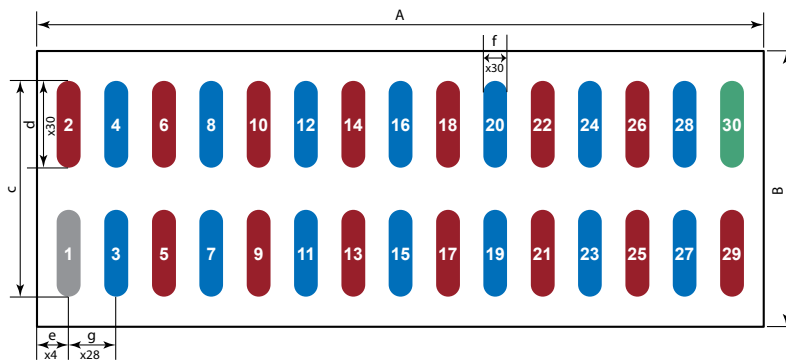
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2206	2206	YYYY	ZZZZ

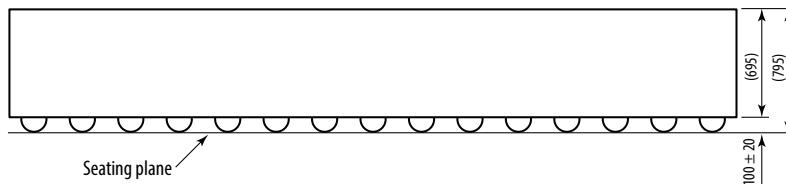
**DIE OUTLINE**

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
g	400	400	400

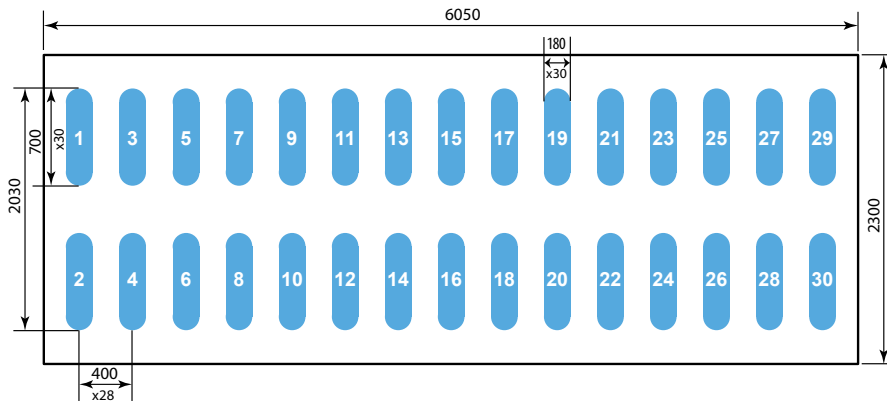
Side View



Pad 1 is Gate;  
**Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;**  
**Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;**  
**Pad 30 is Substrate.\***

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )

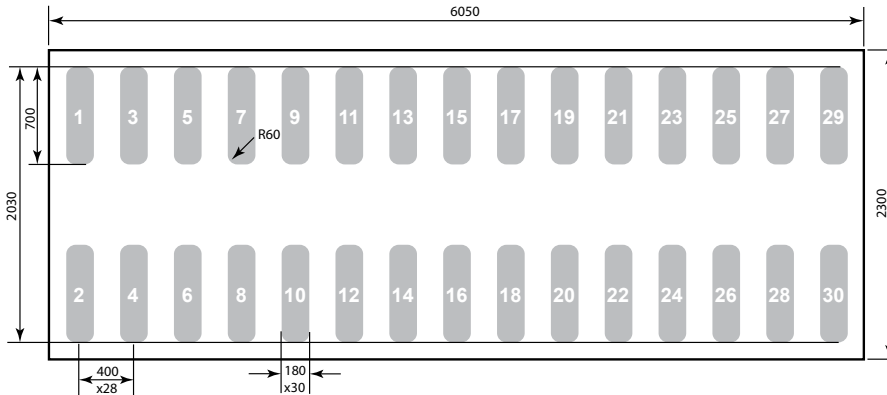


Land pattern is solder mask defined.

- Pad 1 is Gate;
- Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;
- Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;
- Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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Revised June 2022